

First Name	Last Name	Company
Gary	Adam	Keysight Technologies
guy	addis	Radiall
Nikhil	Adnani	ThinkRF
Yukinao	Ajlani-Hashimoto	Kikusui Electronics Corporation
Jorgen	Akerlind	Swedish Defence Materiel Administration
Sergei	Akimtsev	Universal Switching Corporation
Hussain	Al-Asaad	University of California
Norton	Alderson	Universal Switching Corporation
Igor	Aleksejev	Tallinn University of Technology
Hayder	Al-Hraishawi	Southern Illinois University
Faisal	Ali	MUSHKO Electronics Pvt Ltd
Gerald	Allgaier	DynamicSignals LLC
Kevin	Almanza	Keysight Technologies
Candy	Ambrose	AUTOTESTCON 2016
Tony	Ambrose	Tektronix
Mike	Amos	USMC
Jack	Amsell	DSI International, Inc.
Jack	Amsell	DSI International, Inc.
Mohamed	Andasmas	Cyclam
Valerie	Andrew	Elma Electronic Inc.
Philip	Angelotti	HyTech Associates, Inc.
Serguei	Antonov	Regional Avionics Repair LLC
Ken	Applebaum	COTSWORKS
John	Ardussi	Innovative Aerospace Technical & Marketing Consultants
Matt	Arick	TEVET LLC
Tom	Armes	IntraStage

Tim	Armstrong	Parker
Gustavo	Arredondo	Para Tech
George	Asai	Kikusui Electronics Corporation
Hayati Cem	Atakan	DEICO Muhendislik A.S.
Larry	Attkisson	Northrop Grumman
Charlie	Badzik	TMS
Yong-Soo	Bae	ADLink Inc.
Braum	Bahrampour	The Boeing Company
Dave	Bailey	Elma Electronic Inc.
Jimmy	Bailey	USAF
Joe	Baker	Fluke
David	Baker	G Systems, LP
Mark	Balderas	Advanced Circuits
Neil	Baliga	Verifide Technologies, Inc.
Jim	Balistreri	RD & D Sales Engineering
Curt	Ball	W5 Test Solutions, Inc.
Thanh	Banh	NAVAIR ISSC
Marco	Barahmand	
Alex	Barbosa	EMBRAER
Todd	Bardell	BAE Systems Australia
Matt	Baron	Marvin Test Solutions
Kelly	Barrows	Raytheon
Jeff	Barry	Ward Davis Associates
Rick	Bartholomew	IXI Technology
Adam	Bartleson	Crane
Eric	Bean	Honeywell FM&T
Roddy	Beat	Segin Global Solutions
Lyle	Beck	NAVAIR Jacksonville

Kevin	Beenfield	Hill AFB
JD	Beitzinger	Test Midwest
Mike	Belbot	northrop grumman
Joseph	Benko	Para Tech
Mark	Bennett	Psi Solutions
Paul	Bennett	Acculogic Inc
Davette	Berry	Astronics Test Systems
Richard	Bertea	Smart Electronics
Raymond	Beshears	DSI International, Inc.
Paul	Bessette	Southern Marketing Associates
John	Billingsley	Northrop Grumman Corp.
William	Birurakis	Pioneering Decisive Solutions Inc., PIDESO
Ken	Bisson	AIT
Anirban	Biswas	Virginia Panel Corporation
Mike	Bivens	R&D Interconnect Solutions
Brandon	Black	Liberty Test Equipment
Jeffrey	Blake	Northrop Grumman
Jim	Blakeley	Alcon
Russell	Blankenship	USAF
Fred	Blönnigen	Bustec
Chris	Boggs	MAC Panel
George	Bollendorf	Empower
Giuseppe	Bondi	DOW-KEY MICROWAVE
Steven	Booth	Boeing
Tom	Boris	SAE-NASA Tech Briefs
Joseph	Bosas	Honeywell FM&T
Paul	Bouagnon	National Instruments
Paul	Bovingdon	Pickering Interfaces

Adam	Bowersox	USAF
Paul	Braden	Air Force
Thomas	Bradford	U.S. Marine Corps
Tatum	Bradley	Logisys Technical Services
Tina	Bragg	Product Director, TMDE
Gary	Branch	GD Branch
Skylar	Bratcher	USAF
Scott	Braun	MTE
Tom	Bresnan	R&D Interconnect Solutions
Lyn	Bresnen	PEI-Genesis
Bill	Breyer	Ward Davis
Julie	Briggs	VT Miltope
John	Brock	The Boeing Company
Dennis	Brockway	Southern Marketing Associates
Glen	Broderick	Electro Rent
Malcolm	Brown	UK MOD
Gerald	Brown	The Boeing Company
Ronald	Brown	Astornics Test Systems Inc.
Katie	Brown	Excalibur / Transcat
Mark	Brown	Versatile Power
Annina	Brown	PPCLA
Rick	Buddine	BIT CORP
M	Bunge	Goldenwest Sales & Associates
Steven	Butcher	SWB Associates
Adrian	Butoi	Chroma Systems Solutions, Inc.
Alan	Butterworth	Marine Corps Logistics Base
Bill	Byrnes	Teradyne
Timothy	Cahaney	L-3 Communications

Mark	Cain	USAF
Brennan	Caissie	Pickering Interfaces
Gerry	Camacho	P1dB
Christopher	Camargo	Southwest Research Institute
David	Campbell	MITRE
Brad	Canfield	TDK-Lambda Americas
Weizhou	Cao	MTCS
David	Carey	Wilkes University
Calvin	Carlson	WesTest Engineering
Thomas	Carlsson	Saab Technology
Robert	Carr	TPS Associates, Inc.
Michael	Carter	IXI Technology
Matthew	Carter	Keysight Technologies
Carlos Eduardo	Cassiano Pinto	EMBRAER
Terrence	Chan	Raytheon
John	Chapman	The Boeing Company
John	Chapman	Boeing
Shivansh	Chaudhary	National Instruments
Madhur	Chawla	Transline Technology, Inc.
Yung-Pin	Cheng	National Central University
Erik	Chowdhury	Raytheon
Kevin	Christensen	USAF Hill AFB
Kevin	Christensen	309 SMXG Software Maintenance Group
David	Christensen	USAF Hill AFB
Paul	Clark	Telemakus LLC
Lisa	Clayton	Pickering Interfaces
Rajkumar	Clement	Qmax Test Equipment Pvt Ltd
Christopher	Clendenin	The Boeing Company

Jennifer	Coats	National Instruments
Mark	Coe	COASTAL COMPONENT INDUSTRIES, INC.
Don	Coe	COASTAL COMPONENT INDUSTRIES, INC.
Tom	Cole	MTE
Alan	Collazo	Hytech Associates Inc.
Thomas	Combass	Fleet readiness Center Souteast
Tony	Conard	US Navy
Tony	Conard	Fleet Readiness Center
John	Condon	Marvin Test Solutions
Royal	Cook	Parker Hannifin
Heather	Cooke	Pioneering Decisive Solutions Inc., PIDESO
Jim	Cooney	AMETEK Programmable Power
Alex	Cordero	AMASCO
Randy	Core	Lockheed Martin
Kathy	Cornett	Astronics Test Systems Inc
Kathy	Cornett	Astronics Test Systems Inc
Casey	Coyne	TEVET LLC
Richard	Crabtree	Ducommun
Grover	Craig	JTAG Technologies
David	Cravey	
Lorilee	Crisp	
Nick	Crisp	Arrowhead Technical Sales
Brian	Crisp	Arrowhead Technical Sales & Marketing, LLC
Jim	Crosson	Huntron Inc
Joe	Cuccaaro	US Army
Xiuhai	Cui	Harbin Institute of Technology
Enos	Cummings	US Air Force
Andrew	Cunningham	Draper Laboratory

Pat	Curry	Army
Bill	Curry	Huntron Inc
Patrick	Cushing	Raytheon
Jeff	Cuthbertson	Edge Consulting and Sales
Brian	Cyrer	
James (Jim)	Dagel	Harris Canada Systems Inc
Mo	Dagher	Parker Aerospace
Jared	Dalpias	309 SMXG Software Maintenance Group
Jared	Dalpias	USAF--309th SMXG
Milan	Damnjanovic	Tyonek Engineering & Agile Manufacturing
Marie	Darling	Harris Canada Systems Inc
Glenn	Darrow	IXI Technology
Jean	Dassonville	Keysight Technologies
Randy	Davis	I MEF G6
Edward "Ed"	Davis	OPHIR RF
Chuck	Davis	TMS
Timothy	Davis	Fleet Readiness Center Southeast
Sheryl	Davis	USAF
Noah	De La Hunt	Fleet Readiness Center East
Craig	De Paul	DSI International, Inc.
Ryan	De Paul	DSI International
Jeroen	de Zoeten	DAP Technology
Mary	Dean	Teradyne
Seth	DeCato	USAF
Jim	Deffler	NAVAIR
Pierre	Degauque	University of Lille
Mert	Degerli	DEICO MUHENDISLIK A.S.
Thomas	DeGrood	NAVAIR, North Island

Robert	Deibner	Corelis
Jason	delaTova	Windward Energy Company
Gérard	Delfour	SPHEREA
Dawei	Deng	Beihang University
Michael	Dent	Michael B Dent Consulting
Naresh	Deo	QuinStar Technology, inc.
Stephen	Desantis	
Larry	Desjardin	Modular Methods
Michael	Dewey	Marvin Test Solutions
Mike	Dewey	Marvin Test Solutions
Ankit	Dhanadia	Ducommun
Paul	Dhillon	INTEGRA DEVICES
Sourabh	Dhillon	INTEGRA DEVICES
Alan	Dicato	Segin Global
Leonard	Dickstein	Spanawave Corporation
Jason	Diggs	Virginia Panel Corporation
Susan	Dillon	Honeywell
Douglas	Dillon	Raytheon
Jason	Dip	Marvin Test Solutions, Inc.
Tom	Dirienzo	Keysight Technologies
Manish	Dixit	Qmax Test Equipment Pvt Ltd
Anne	Dlugosz	NAVAIR
Todd	Doduy	Wes-K
John M.	Doherty	PENCOM
James	Donald	Northrup Grumman
Dan	Donati	Astronics Test Systems
Edward	Dou	Raytheon
Walter	Downing	Southwest Research Institute

Bill	Driver	National Instruments
Matthew	Dru	Cain Technology
Andre	Dubois	Tritek Solutions
Dan	Dunn	Keysight Technologies
Laurie	Dunn	
Bryan	Dutton	Parker Aerospace
Eric	Ehlers	TIP
Jan	Ellis	AUTOTESTCON 2016
Mike	Ellis	AUTOTESTCON 2016
Adam	Elovitz	Elotek Systems
Mike	Elovitz	Elotek Systems
Scott	Elson	Rohde & Schwarz, USA Inc
Dave	Elwell	Textron Systems
Richard	Ely	Raytheon Missile Systems
Tim	Endo	L-3 IEC
Jordan	Ensminger	OPHIR RF Inc.
Tony	Erwin	Teradyne
Jim	Esmay	Cain Technology
Gregory	Evans	WelComm, Inc
Chris	Evelo	Dytec/Midwest
Terry	Eyrolet	IPT
Steve	Fairbanks	Astronics Test Systems
Christopher	Fallon	Northrop Grumman
Rutherford	Fauni	Ducommun
Peter	Fei	Chroma Systems Solutions, Inc.
Dan	Fenger	Technologies West RMS
Cristian	Fernandez	Professional Guest
Constantine	Fernando	Integrated Semiconductor Solutions Inc

Dan	Fettner	GA-ASI
Jay	Ficicchy	Ward Davis Associates
Douglas	Firth	Custom Systems Integration, Inc.
Kelly	Fisher	Astronics Test Systems
Matt	Fishman	Spectracom/GMA
David	Fitkin	Excalibur / Transcat
Dan	Fitzgibbon	Astronics Test Systems
Patrick	Flanders	Tessco
Ronald	Fleck	Pulse Electronics
Joseph	Foerstel	CORWIL
Lawrence	Ford	Orion Technologies, LLC
Jay	Forman	Perillo Industries, Inc.
Rick	Forman	Broadcom LTD
Loup	Foussereau	SPHEREA LLC
Robert	Fox	Fleet Readiness Center Southeast
Brian	Fox	NTS
Rick	Foyt	USMC
Craig	Frahm	AMETEK Programmable Power
Jim	Fraine	Marvin Test Solutions
Joseph	Francis	United States Air Force
Joseph	Francis	United States Air Force
Dominic	Frattaroli	Regional Avionics Repair LLC
Stefanie	Frattaroli	Regional Avionics Repair
Rick	Freeman	Lockheed Martin
Chuck	Freihofer	ProTEQ
Michael	Frey	Marvin Test Solutions
Gary	Friske	Pacific Power
Darrel	Fritts	DSI

Curtis	Froland	AMETEK Programmable Power
Melissa	Frulla	QU
Shaun	Fuller	Pickering Interfaces
John	Funk	Skyline Orange County
Sangram	Gaikwad	VTI Instruments
Kathy	Galletta	Liberty Test Equipment
Eric	Gao	AIV SYSTEM INC
Gilbert	Garcia	NAVAIR
Javier	Garcia	Marvin Test Solutions
Javier	Garcia	Marvin Test Solutions
Donald	Gardner	DRS Technologies
Hector	Gavilla	ATTI
George E	Geathers	N/A
Chris	Geiger	Lockheed Martin
Gary	Geil	Spectracom/GMA
greg	geiss	Vanderveer Plastics
Fernando	GenKuong	VTI Instruments
Rajeev	Ghimire	University of Connecticut
John	Gibson	United Intelligence Corporation
Al	Gibson	Santa Barabara Infrared
Pavel	Gilenberg	Teradyne
James	Giubilato	AMASCO
Bill	Gleason	Para Tech
Mark	Gohr	Teradyne
Robert	Goldberg	RMGA Consulting
Andrew	Goldfarb	Draper Laboratory
Chris	Gorringe	MOD Contractor
Erick	Gorszwick	Advantech Corporation

Eric	Gould	DSI International, Inc.
Kevin	Gould	U.S. Army
Art	Graafmans	Newland Design + Assoc. Inc.
Brad	Grams	Huntron Inc
Bryant	Grand	JTAG Technologies
Graham	Green	National Instruments
Bill	Green	Pickering Interfaces
Douglas	Green	Psi Solutions
Charles	Greenberg	Astronics Test Systems
Ramsey	Greene	National Instruments
Brandon	Greenley	Tektronix, Inc
Andrew	Gresham	BAE Systems Australia
Patricia	Griffin	Astronics Test Systems
Curtis	Grigg	Elotek Systems, INC
Sean	Grigorian	Cain Technology
Steve	Grodt	Chroma Systems Solutions, Inc.
Paul	Groome	Digitaltest, Inc.
Kenneth	Grossman	Honeywell International
Ammon	Gruwell	Brigham Young University
Al	Guarino	Spectracom/GTEK
Christopher	Guerra	Southwest Research Institute
Jim	Guinaw	Astronics Test Systems
Aydin	Guney	ASELSAN Inc.
Peng	Guo	Boeing Company
Steve	Gurr	Electro-Meters
Adrian	Gustai	DOD
Sergio	Gutierrez	Raytheon
Loofie	Gutterman	Marvin Test Solutions

Dafna	Gutterman	Marvin Test Solutions, Inc.
BRIAN	GUY	COASTAL COMPONENT INDUSTRIES, INC.
John	Gyurek	SAIC
Andy	Haber	
Andy	Haddad	VTI Instruments
Eric	Hahn	EMSCAN
Elton	Hall	Pickering Interfaces
Rosemarie	Hall	TRI*Net, Inc.
James R.	Hall	TRI*Net, Inc.
Eric	Haltiner	JTAG Technologies
Brooks	Hanley	Keysight Technologies
Derwin (Dex)	Hansard	PMA260, Common Aviation Support Equipment
Ruidong	Hao	Linktron
David	Harman	SIL Robbin
Rob	Harris	TEVET LLC
Leonard	Harris	MJLM
Roderick	Harvey	Teal Electronics Corporation
Christine	Hawley	
William	Headrick	Lockheed Martin
Christopher	Heagney	NAVAIR Jacksonville
Michael (Mike)	Hearns	Harris Canada Systems Inc
Martin	Heffler	Test-Rep Associates, Inc.
Carl	Heide	National Instruments
Michael	Heilman	PIDESO
Mike	Heineman	Self
Craig	Heitmann	G Systems, LP
Bob	Hesel	Bode Enterprises
Wayne	Helton	MAC Panel

Fabian	Hemmann	Hartmann Electronic
Justin	Hendricks	Keysight Technologies
Jeho	Heo	Ajou university / KTL
Felipe	Hernandez	Global Strategics Solutions LLC
Carlos	Hernandez	Global Strategic Solutions LLC
Bob	Heston	L-3 Communications
Tim	Hide	GRF-LWV
David	Hieger	Eclipse
Jim	Hill	MAC Panel
John	Ho	Marway Power Solutions
Kenny	Ho	ALLIMAGING SYSTEMS
Thien	Ho	MSA
Richard	Hochberg	Retired
Jeannie	Hochberg	AUTOTESTCON 2016
Debra	Hoffman	Lockheed Martin
Linda	Holtkamp	Marvin Test Solutions
Blake	Holton	Evaluation Engineering
Katherine	Homan	Cortek Test Solutions
Blake	Homan	Cortek Test Solutions
Anthony	Hooks	
Robert	Hoover	Teradyne
Mark	Horner	TecRep Corporation
Felix	Horton	Astronics Test Systems
Xueqing	Hou	MTCS
Joseph	Howard	USAF
Alan	Howard	Huntron Inc
Debra	Howard	Astronics Test Systems
Ross	Hrynewych	USMC

Brian	Hsu	AC Power Corp.
Wuhui	Hu	Linktron
Ken	Hu	Virginia Panel Corporation
Johnson	Huang	GWINSTEK
Mike	Hughes	EE-Evaluation Engineering
Noman	Hussain	Pickering Interfaces
Erkan	Ickam	EMSCAN
Kiyoto	Igawa	Kikusui America, Inc.
Koray	Incki	Adana Science and Technology University
John	Irza	Ridgetop Group, Inc.
George	Isabella	BAE SYSTEMS
Larry	Israel	CDI/M & T Company
Shannon	Ivanchev	Pioneering Decisive Solutions Inc., PIDESO
Pam	Jacobs	Astronics Test Systems
Robin	Jacoby	Test Execs LLC
Anand	Jain	National Instruments
KS	Jang	Testmation
Roland	Jansson	Saab
Dave	Jensen	WesTest Engineering
Steve	Jochim	Panasonic
Jonathan	Johnson	Icore International, Inc.
Dale	Johnson	Marvin Test Solutions
Brad	Johnson	General Atomics Aeronautical
Arthur	Johnson	ViaSat Inc.
Keith	Johnson	Conquest Technical Sales
Bonnie	Johnson	Astronics Test Systems
David	Johnson	US Army
Dave	Johnston	Astronics Test Systems

Randy	Johnston	Test Midwest
Cindy	Jones	Custom Systems Integration, Inc.
Derek	Jones	Custom Systems Integration, Inc.
Dave	Jones	Custom Systems Integration, Inc.
Tony	Jones	Harris Canada Systems Inc
Greg	Jones	Astronics Test Systems
Tom	Jones	ION Corporation
Ryan	Jones	Corelis, Inc
Tim	Juan	ADLINK Technology Inc.
Kevin	Judson	Keysight Technologies
Artur	Jutman	Testonica Lab
Jahan	Kakvand	BCI
Ali	Kalbali	Flex
Victor	Kamikubo	Thales Avionics, Inc.
Orr	Karny	Marvin Test Solutions
Shalom	Kattan	Carmel
Daniel	Kattan	Carmel Instruments
Karen	Kattan	Carmel Instruments
Shimon	Katzav	
John	Kauffman	Rockwell Collins
Mark	Kaufman	AUTOTESTCON 2016
David	Kaushansky	Teradyne
Hajime	Kawano	SDK, Inc.
Bryan	Kellogg	Rantec Power Systems, Inc.
Patrick	Kelly	Viasat, Inc.
Kent	Kendra	R&D Interconnect Solutions
Lawrence	Kent	Draper Laboratory
John	Kesser	BAE Systems

Ben	Keynejad	TRI-FAB Associates, Inc.
Valeriy	Khaldarov	CEMsol
Nash	Khouzam	Marvin Test Solutions
Yoochul	Kim	Testmation
Gene	Kim	Teradyne
Jeff	King	Analog Test Engines
Larry	Kirkland	WesTest Engineering Corporation
David	Kirkland	RD&D Sales Engineering
Ronald	Kleinschmidt	TecRep Corporation
Tim	Klimasewski	Spectracom
Skye	Klyve	ION Corporation
Stephan	Koch	Zurich Instruments
Mesut	Koch	Liberty Test Equipment
Chuck	Kochel	Astronics Test Systems
Chuck	Kohfeldt	Astronics Test Systems
Siva Manohar Reddy	Kommireddy	ORION TEST SYSTEMS & AUTOMATION
John	Koontz	National Instruments
Linda	Kovar	AUTOTESTCON 2016
Rocky	Kovar	Self Employed
Moses	Koyabe	Ideal Aerosmith, Inc.
Patricia	Krenzke	Northrop Grumman
Joseph	Krstulic	Honeywell
Scott	Kruth	Marvin Test Solutions
VICTOR	KUNG	CORTEK TEST SOLUTIONS
Mark	Kupferberg	Kepeco, Inc.
Robert	Kupferberg	Kepeco Power
Robert	Kurkjian	HRL Laboratories - Retired
Sochyun	Kyong	Testmation

David	Labore	Pioneering Decisive Solutions Inc., PIDESO
Michele	Labrecque	Keysight Technologies
David	LaCascia	Specialty Software
Art	LaMarchina	
Brian	Landy	Microwave Journal
Andy	Lang	Rockwell Collins
Steven	Langley	USAF
Nick	Lanners	General Dynamics
David	Lasater	USAF
Jim	Lauffer	DSI International, Inc.
John	Lawrence	Consulting
Liberty Test Equipment	Lead Retrieval	Liberty Test Equipment
Tevet	Lead Retrieval	TEVET LLC
Lind Electronics	Lead Retrieval	Lind Electronics
Tom	Lecklider	Evaluation Engineering
Kevin	Leduc	National Instruments
Mel	Lee	e360microwave.com
Yonghoan	Lee	Testmation
Philip	Lee	Parker Aerospace
Thomas	Leininger	Ducommun
Brian	Lennox	Custom Systems Integration, Inc.
David	Levine	Ducommun Inc
Samuel	Lewis	Lewis Consulting
Max	Li	GDW Technology Inc
Changjie	Li	MTCS
Eddy	Liano	ITW Formex
Merielle	Liao	Marvin Test Solutions
Anton	Lin	Axiomtek

Louis	Lin	Skywave
Mason	Lin	Skywave
Peter	Lindahl	MIT
Miha	Linte	Pioneering Decisive Solutions Inc., PIDESO
Gil	Lipper	Advanced Technical Marketing
Hong	Liu	Zodiac Aerospace
Zhaoqing	Liu	Harbin Institute of Technology
Tommy	Ljung	Saab Technologies
Christer	Ljungdahl	National Instruments
Teresa	Lopes	Teradyne
Eduardo	Lopez	EMSCAN
Lynda	Lopez	Marvin Test Solutions, Inc.
Javier	Lopez	Technologies West
Eric	Lord	Pacific Power Source
Dave	Lorelli	Ward Davis Associates
Dennis	Lovell	Measurement Instruments
Rob	Low	Axiom Test Equipment
Robert	Lowdermilk	RADX Technologies, Inc.
Diuane	Lowenstein	Keysight Technologies
Raelyn	Luckow	Skyline Orange County
Jeffrey	Lum	Astronics Test Systems
Joel	Luna	Frontier Technology, Inc.
Glenn	Lundy	Logisys Technical Services
Mark	Lupo	Draper Laboratory
Dan	Lynch	Spectracom
Michael	Lynn	KJS Marketing
Peter	Lyon	Ward Davis Associates
Earl	Lyons	Acquired Data Solutions

James	Lytle	Fleet Readiness Center East
Doug	MacClymont	Dynamic Technology Inc.
Marc	Majewski	MTE Corporation
Mike	Malesich	NAVAIR
Pat	Malone	Harris Canada Systems Inc
Marlo	Manaloto	Keysight Technologies
Scott	Mann	Jetronics Company
Martin	Mannion	Pulse Electronics
David	Manor	Marvin Test Solutions
Stephen	Manrique	USAF
Stephen	Manrique	309 SMXG Software Maintenance Group
Michelle	Manson	Astronics Test Systems
Andre	Marais	AMETEK Programmable Power
Greg	Marinez	DOW-KEY MICROWAVE
Charles	Marino	BAE Systems
Randall	Marion	The Boeing Company
Miriam	Marron	DOW-KEY MICROWAVE
Andy	Martin	Powertec Motors
bella	martinez	Axiomtek
Norm	Matice	TMDE
Naohiko	Matsumura	Kikusui Electronics Corporation
Dean	Matsuura	Teradyne
dean	matsuura	Teradyne
Douglas	Matthes	Marvin Test Solutions
JOHN	MAUL	Diagnosys Systems, Inc.
Daniel	Mayo	SpaceX
Ollie	McConnell	Innovative Integration
Shawn	McCoy	COASTAL COMPONENT INDUSTRIES, INC.

Ed	McDonald	in-phase technologies
Jeff	McFarland	VTI Instruments
Michael	McGoldrick	Teradyne
Steve	McHugh	Santa Barbara Infrared
James	McKechnie	Santa Barbara Infrared
Douglas	McKinney	Maccor, Inc.
Todd	McMullin	Carmel Instruments
Dan	McNair	D & K Systems
Ralph	McNeal	
Timothy	McNish	Alcon Labs
Arlene	Meadows	Global Test Solutions
James	Mecredy	Bal Seal
Bruce	Melcher	USMC
Thomas	Melle	HIGHVOLT
Galina	Melnyk	Excalibur / Transcat
Bill	Mengert	DSI International, Inc.
Steve	Mensh	Textron Systems
Tom	Merline	Everett Charles Technologies
Mike	Messina	Spectracom
Joseph	Mikolaj	Independent Contractor
Donald	Miller	Tritek Solutions, Inc.
Brian	Miller	Teradyne
Mitch	Miller	USAF
Chris	Miller	Keysight Technologies
Anthony	Minei	Lockheed Martin
Mukund	Modi	NAVAIR
Azim	Mohammed	DapUSA Inc.
Marc	Monnin	USAF

Fred	Moore	The Boeing Co.
Keith	Moore	Pickering Interfaces
Matthew	Morgan	NAVAIR
Bob	Morrell	Advanced Technical Marketing
Sandy	Morris	VT Miltope
Rob	Mortensen	Analog Test Engines
Robert	Mortenson	Keysight Technologies
Eric	Moser	Ridgetop Group, Inc.
Joe	Mueller	Keysight Technologies
James	Mulato	Astronics Test Systems
Chris	Mulkey	MOHR Test and Measurement
david	mullin	keysight
Ray	Munden	AR Modular RF
Ariadne	Murdy	Integrated Procurement Technologies
Jerry	Murphree	DRS Technologies
Timothy	Murphy	The Boeing Company
Jeff	Murrill	Northrop Grumman
Paul	Najdowski	USAF
Tim	Navickas	Honeywell
Ion	Neag	Reston Software
Andrew	Nelsen	Chroma Systems Solutions, Inc.
Greg	Nelson	Harris Canada Systems Inc
Mark	Nelson	Southern Marketing Associates
Guy	Newton	NAVAIR ISSC North Island
Ming	Ng	Moog
Tran-Chau	Nguyen	309th SMXG
Kelvin	Nguyen	Thales InFlyt Experience
Lanh	Nguyen	Boeing

Johnny	Nguyen	Astronics Test Systems Inc
Steven	Nguyen	Alcon
Harry	Nguyen	Alcon Research
Diep	Nguyen	Alcon Laboratories
Ken	Nguyen	Alcon
Allen	Nguyen	General Monitors by MSA
Quy	Nguyen	Boeing
Alex	Nichols	
Todd	Nielsen	Circuit Check, Inc.
Philip	Niosi	DRS Technologies
Tetsushi	Nishida	Y-MAX, Inc.
Shayne	Nofts	Chroma Systems Solutions, Inc.
Mitsuhiro	Noguchi	Newly-T
Sanguk	Noh	The Catholic University of Korea
Jeff	Norris	IXI Technology
Esra	Nurgun	ASELSAN INC
Ilyas	Nuri	Keysight Technologies
Tami	O'Brien	MTE Corporation
Robert	O'Brien	Draper Laboratory
Steve	O'Donnell	Lockheed Martin
Steven	O'Donnell	Lockheed Martin
Bengt	Ohlsson	Swedish Defence Materiel Administration
Jack	Okabayashi	VMSI
James	Okon	Dytec Midwest
Laura	Oleson	AUTOTESTCON 2016
Alan	Oleson	AUTOTESTCON 2016
MANNY	OLMEDO	ASSOCIATED TECHNICAL SALES
Jeff	Olsen	

Jerome	Olsen	Astronautics Corporation
Jens	Olsen	L-3
Stephen	Oonk	American GNC Corporation
Thomas	Opheim	SAIC
James	Orlet	Boeing
Leslie	Orlidge	Independent Consultant
Mitchel	Orr	Pacific Power Source
Barry	Orr	NASA-JPL
KAREN	ORTEGON	MARVIN TEST SOLUTION
MARIE	ORTEGON	MARVIN TEST SOLUTION
KAREN	ORTEGON	MARVIN TEST SOLUTION
Roger	Ortegon	Marvin Test Solutions
Darcy	Ortiz	Marvin Test Solutions
Francisco	Ortiz	CNyN UNAM
Jamie	O'Sullivan	The Boeing Company
Kim	Otte	Pickering Interfaces
Ken	Ovens	Teradyne
Scott	Owens	Teradyne
Volkan	Özdemir	ASELSAN Inc.
John	Page	Keysight Technologies, Inc.
Joe	Paglione	Eastern Instrumentation
Joe	Paglione	in-phase technologies
Rob	Pagones	RWP Electronic Sales
Michael	Pantalon	Peregrine Semiconductor
Tad	Papineu	
Lynda	Parada	IXI Technology
Anthony	Parker	Johns Hopkins APL
Kevin	Parmenter	How2Power

Joshua	Parsley	Pacific Power Source
Navin	Patel	The Boeing Company
Mike	Paturzo	Textron Systems
Donald	Peacock	National Instruments
Robert	Penny	Teradyne
Terry	Penny	DRS Technologies
Mike	Penta	Giga-tronics, Inc
Mark	Perko	Tritek Solutions Inc.
Logan	Perreault	Montana State University
Joshua	Perry	Holzworth
Bruce	Peterson	Accolade Engineering Solutions
Craig	Petrie	Innovative Integration
Elton	Phan	Thales Inflight Avionics
stan	pierson	prairie dynamics
Bryan	Pippins	IXI Technology
Janet	Pippins	IXI Technology
Jerry	Pirk	I MEF
Michael	Pluchar	Ward Davis
Vincent	Posner	Santa Barbara Infrared
Jerry	Price	Versatile Power
Brian	Price	Astronics Test Systems
Hugh	Pritchett	Analysis, Integration & Design, Inc.
Liyan	Qiao	Harbin Institute of Technology
Jin	Qiao	IXI Technology
Tony	Quach	Bal Seal Engineering
Rex	Radabaugh	COTSWORKS
Reid	Raithel	Moog Aircraft Group
Narayanan	Ramachandran	RAMA Systems LLC

Bob	Rassa	Raytheon
Brandon	Rathbun	Space Electronics LLC
Mary	Rathbun	Space Electronics LLC
Shawn	Readenour	Vidac Solutions
Reggie	Rector	National Instruments
Paul	Reese	Pioneering Decisive Solutions Inc., PIDESO
Kirk	Reger	Ward Davis
Tim	Reilly	Apex Technovations
Jim	Renwick	MAC Panel
Antonio Carlos	Ribeiro Neto	EMBRAER
Daniel	Richardson	Hill AFB
Christopher	Richardson	USAF
Tony	Ricker	AIT
Kara	Riley	Astronics
Greg	Riley	
Cliff	Robins	NAC Semi
Ben	Robinson	National Instruments
Dave	Rocker	Virginia Panel Corporation
Richard	Roddis	Fluke Calibration
Andrea	Roderick	NAVAIR
Mona	Rodriguez	Universal Switching Corporation
Jesse	Rogers	Everett Charles Technologies
Greg	Rollins	BAE Systems
Jay	Romania	US Army
Pablo	Romero- Estevez	Axiom Test Equipment
Nicole	Rorick	DOW-KEY MICROWAVE
Wayne D	Rorick Jr	DKM VTA
Jim	Rose	Keysight Technologies

Gordon	Ross	Qualitel Corp
Bill	Ross	US Navy
James	Roth	NAVAIR
Bob	Rowley	MAC Panel
Andreas	Ruben	W-IE-NE-R Plein & Baus Corp.
Marshall	Rubin	IEEE Media
Jeff	Rubin	JNRA
Michael	Rutledge	
S R	Sabapathi	Qmax Test Equipment Pvt Ltd
Varun	Sabapathi	Qmax Test Equipment Pvt Ltd
Fred	Sabatine	Chroma Systems Solutions, Inc.
Isaac	Saenz	Raytheon
Hussain	Saijad	Telec
David	Salisbury	Northrop Grumman
Soumaya	Sallem	WIN MS
Lou	Salzano	Astronics Test Systems
Abhay	Samant	National Instruments
Richard	Sandate	The Boeing Company
Robert	Sanders	DRS
Tom	Sanders	Stellar Engineering
Lorena	Sandoval	
Manuel	Sandoval	Diehl Controls de Mexico
Greg	Sapp	Artisan Electronics, Inc.
Tom	Sarfi	VTI Instruments
Steve	Sargeant	Marvin Test Solutions
Howard	Savage	
Chris	Savalia	Transline Technology, Inc.
Dawn	Savidge	TEVET LLC

Richard	Savidge	Savidge Consulting, Inc.
Shellie	Schaul	Astronics Test Systems Inc
Shellie	Schaul	Astronics Test Systems
Steve	Schink	Keysight Technologies
Debbie	Schmidt	Lockheed Martin
Michael	Schneider	National Instruments
Wendy	Schneider	General Dynamics
Leonard	Schuler	AIT
Mike	Sciulli	Up Sales, Inc.
Michael	Seavey	Northrop Grumman
laszlo	sebestyen	Jetronics Co. Inc.
Anthony	Sedberry	MAC Panel
Glen	Seebruch	ViaSat
Jon	Semancik	VTI Instruments
Izzet	Serbest	ASELSAN Inc.
Klara	Sesztak	NAVAIR
Bob	Severson	General Atomics - Aeronautical Systems, Inc.
Kevin	Shaffer	ACETEC INC
Ed	Shaffer	USMC
Paul	Shanahan	Pickering Interfaces
Russell	Shannon	Department of the Navy
Robert	Sharman	Device Engineering Incorporated
Joe	Sharp	Signal Processing Devices, Inc.
Jinglong	Sheng	Linktron
Adam	Shepard	Virginia Panel Corporation
Sam	Sheppard	USAF
John	Sheppard	Montana State University
Arthur	Shilling	Fleet Readiness Center Southeast

Suhas	Shinde	Intel
suhas	shinde	Intel
Rex	Shook	Elma Electronic Inc.
yogendra	shrestha	SkyWest
Du	Shuming	Nanjing Research Institute of Electronics Technology
Grant	Sides	Raytheon
Sam	Simione	Spectracom / Contech Marketing
Marc	Simms	COTSWORKS
Kevin	Simpson	Dept of Air Force
Sue	Slagle-Smith	Northrop Grumman Corp.
Sue	Slagle-Smith	Northrop Grumman Corp.
Charlie	Slater	Keysight Technologies
Leo	Smale	Lionheart NW
Steve	Small	Tritek Solutions
Steve	Small	Tritek Solutions
Chris	Smith	USAF
Matthew	Smith	Draper Laboratory
Greg	Smith	RADX Technologies, Inc.
Ross	Smith	RADX Technologies, Inc.
Michael	Smith	US ARMY Aviation and Missile RDEC
Trevor	Smith	Pico Technology
Terry	Smith	X Technologies, Inc.
Bruce	Smith	Marvin Test Solutions
Erik	Soiman	CAEN Technologies Inc.
Pablo	Solis	ViaSat, Inc.
Tracy	Solomon	Tevet
Mike	Somerville	DSI International, Inc.
Jeong	Song	Chroma Systems Solutions

Boon	Spangler	Autotest
Anthony	Sparks	JTAG Technologies
Richard	Spears	DRS Technologies
Michael	Spinali	RADX Technologies, Inc.
Rob	Spinner	ATTI
Ron	Spooner	Ward Davis Associates
Ronald	Stack	North Atlantic Industries
David	Staley	BAESYSTEMS
Joseph	Stanco	TPS Assoc Inc
Michael	Stankey	USAF
Donny	Stanton	Testech
Jennifer	Stark	Keysight Technologies
Bob	Stasonis	Pickering Interfaces
Kevin	Steidel	Eclipse
Robert	Stevens	
Craig	Stoldt	BAE Systems
Jeff	Stowers	Virginia Panel Corporation
Sandy	Stowers	Virginia Panel Corporation
Lennart	Strandh	Custom Systems Integration, Inc.
John	Stratton	Keysight Technologies
Jeremy	Straub	North Dakota State University
Douglas	Strother	L-3 Communications
Dave	Stuart	AMETEK Programmable Power
Randall	Sucamele	Cadia Networks, Inc.
Michael	Sudolsky	Boeing
Scott	Sullivan	Test Execs
Robert	Sullivan	The Boeing Company
Michael	Sullivan	Teradyne

Tim	Sumser	Powertec Industrial Motors
Scott	Sutter	Transcat
Hauw	Suwito	Comware Technical Services
Claude	Sweeton	TEVET LLC
Alan	Szary	Custom Systems Integration, Inc.
Frank	Szilagyi	BAE Systems
Robert	Szpila	Marvin Test Systems
Serge	Taba	Astronics
Tsuneo	Takahashi	NF Corp
Janis	Takahashi	ViaSat
Niko	Takahashi	self employed
Bryan	Takamiya	Cain Technology-Southern CA, Inc.
Terry	Takemori	Ducommun
Linda	Talcott	AMREL/American Reliance
Yasuo	Tanabe	Newly-T
Phil	Tarantino	BAE Systems
Tom	Tavares	CMA Test & Measurement Solutions
Eric	Taylor	Keysight Technologies
Brittany	Taylor	Summit Test Solutions
Ronald	Taylor	Summit Test Solutions
Maureen	Taylor	Summit Test Solutions
Geoffrey	Tecza	VertMarkets, Inc.
Tim	Teffeteller	Para Tech
Andrew	Thiel	UCLA
Scott	Thomas	Raytheon
David	Thompson	Electro-Meters
Edward	Thompson	Marvin Test Solutions
Gary	Tilley	Astronics Test Systems

John	Tinkler	RelComm Technologies, Inc.
Tony	Tirelli	VTI Instruments
Neal	Tomblyn	Lockheed Martin
Halil	Tongul	ASELSAN Inc.
Thanh	Tran	Semtech
Hai	Tran	U.S. Government Accountability Office
Nguyen	Tran	Semtech
Henry	Tran	Boeing Company
TIM	TRAN	Alcon Research Ltd.
Huan	Trang	Advantech
William	Travers	SUNFORCE
Jelena	Trbovic	Zurich Instruments
Vic	Tricamo	Versatile Power
John	Trinh	Pacific Power Source
Troy	Troshynski	AIT
Kevin	Trout	Keysight Technologies
Vincent	Truong	boeing company
Michael	Tschiderer	Transcat
Mike	Tseng	Ampro ADLINK Technology Inc.
Vincent	Tseng	Ampro ADLINK Technology Inc.
Frank	Tseng	AC Power Corp.
Frank	Tso	ACETEC INC.
Carl	Tulberg	Peregrine Semiconductor
Adam	Tuley	ViaSat
Alberto	Tungcab	NAVAIR ISSC
Mirna	Tungcab	BAE Systems
Alberto	Tungcab	NAVAIR ISSC
Drew	Turpin	Ward Davis Associates

Bob	Twiggs	in-phase technologies
Ty	Ung	Hill Air Force Base
Louis	Ungar	ATE Solutions
Steve	Unszusz	W5 Test Solutions, Inc
Önder	Ünver	ASELSAN Inc.
David	Upton	Schmersal
Marta	Urena	Astronics Test Systems
Kenneth	Van	Army
Peter	van den Eijnden	JTAG Technologies
Donald	Vanderweit	Keysight Technologies
Herman	vanEijkelenburg	Pacific Power Source
Martin	Vargas	Teradyne
Luis	Veliz	Chroma Systems Solutions, Inc.
Mark	Vennerholm	Teradyne
Patrick	Verbovsky	NAVAIR
Dorrel	Vernon	TDK Lambda
Kent	Vikstrom	Swedish Defence Material Administration
Jose	Villalobos	Elotek Systems, INC
Steve	Visosky	Spectracom
Andy	Vo	
nelson	vogt	Ametek - VTI Instruments
David	Vondran	Astronics
Kyle	Voosen	NI
Michael	Wagner	AMETEK Programmable Power
Robert	Waldeck	Astronics
Oral	Walker	Product Director, TMDE
Dan	Walsh	Teradyne
Mark	Walters	Williams RDM

Garrett	Wampole	MITRE
Gang	Wang	University of Connecticut
Cheng	Wang	Mechanical Engineering College
Robert	Wang	MTCS
Mitchell	Warren	309 SMXG Software Maintenance Group
Mike	Watts	National Instruments
Albert	Weathersby	Northrop Grumman Corporation
Thomas	Weaver	DRS Technologies
William	Webb	Aster Technologies
Jeremy	Webb	J. Webb Consulting
Iram	Weinstein	Leidos
Jim	Welch	VTI Instruments
Alan	Wells	Ampro ADLINK Technology Inc.
Rodger	Wells	Teradyne
Sam	Weng	Chroma Systems Solutions, Inc.
Craig	Wentzel	Ridgetop Group, Inc.
Gary	Westmoreland	Keysight Technologies
Phil	Wheeler	Power Engineering Consultants
Kevin	Wheeler	Pickering Interfaces
David	Whetstone	Goepel Electronics
Ian	White	Gaddon Ltd / Gaddon Australia
Tom	Wilkins	Rantec Power Systems Inc.
Tom	Wilkins	TMS
Kelly	Williams	USAF - AFLCMC
Wilbert	Wilson	Teledyne Controls
Alan	Wilson	The Boeing Company
Dave	Wilson	MAC Panel
Russell	Wingard	

Samuel	Winters	DOD, U.S. Navy, NAVAIR, PMA260
Mike	Winters	Elotek Systems, INC
Joe	Wirth	Excalibur / Transcat
Jason	Wirth	Rockwell Collins
Ringo	Wong	Virginia Panel Corporation
Larry	Wong	Boeing
John	Wood	Teradyne
Jesse	Woolridge	Universal Switching Corporation
Scott	Wrinkle	Versatile Power-TRS Rentelco
Joshua	Wu	Raytheon Canada Ltd
Lingling	Wu	KeLiang (HK) Limited
Thomas	Wychock	Keysight Technologies
Yang	Xu	MTCS
Hiroimi	Yamashita	SML, Ltd.
Gui	Yan	Linktron
Cai Xia	Yang	University of North Dakota
Bo	Yao	MTCS
Ron	Yazma	Marvin Test Solutions
Jinlin	Ye	MTCS
Yang	Yu	Harbin Institute of Technology
Jesse	Zapata	NAWCWD
Chungliang	Zeng	MTCS
Yumi	Zhang	UCLA Anderson School of Management
William	Zieg	USAF Robins AFB
Bonnie	Ziegler	TDK-Lambda Americas
Matthew	Zielinski	Teledyne Controls
Yijun	Zou	KeLiang (HK) Limited
Patrick	Zylmans	Technical Diagnostic Services